

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/067,425	VAN VEEN ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Scott B. Geyer	2829	

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	B	US-6,492,737	12-2002	Imasu et al.	257/778
	C	US-6,225,206	05-2001	Jimarez et al.	438/616
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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